

Inquiry Into Counterfeit Electronic Parts in the Department of Defense Supply Chain, May 2012

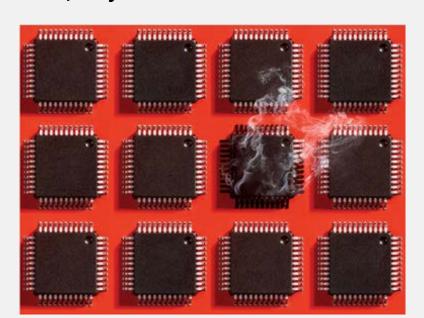
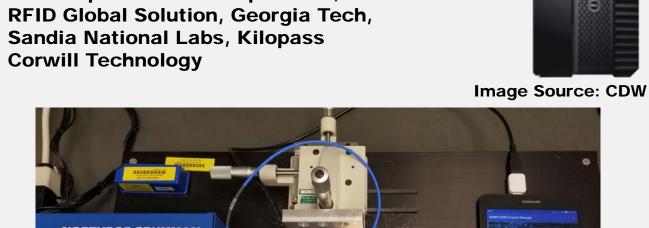
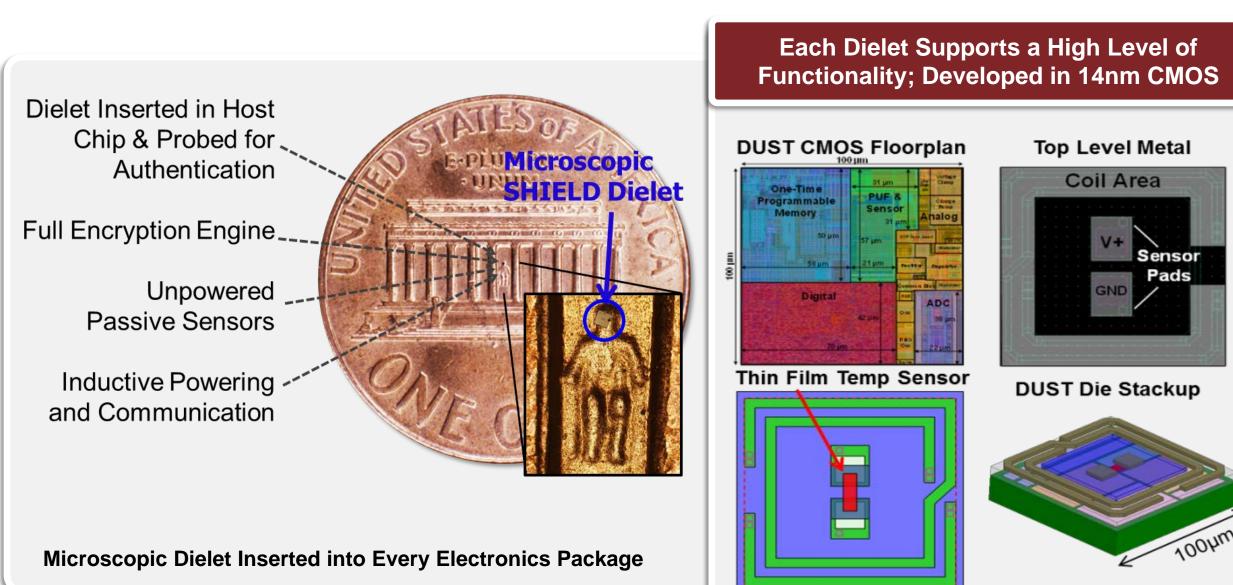


Image Source: IEEE Spectrum







Wafer Scale Probing of Dielets uses Test Controller, Maximizing Dielet Density on Wafer, Minimizing Test Time and Cost

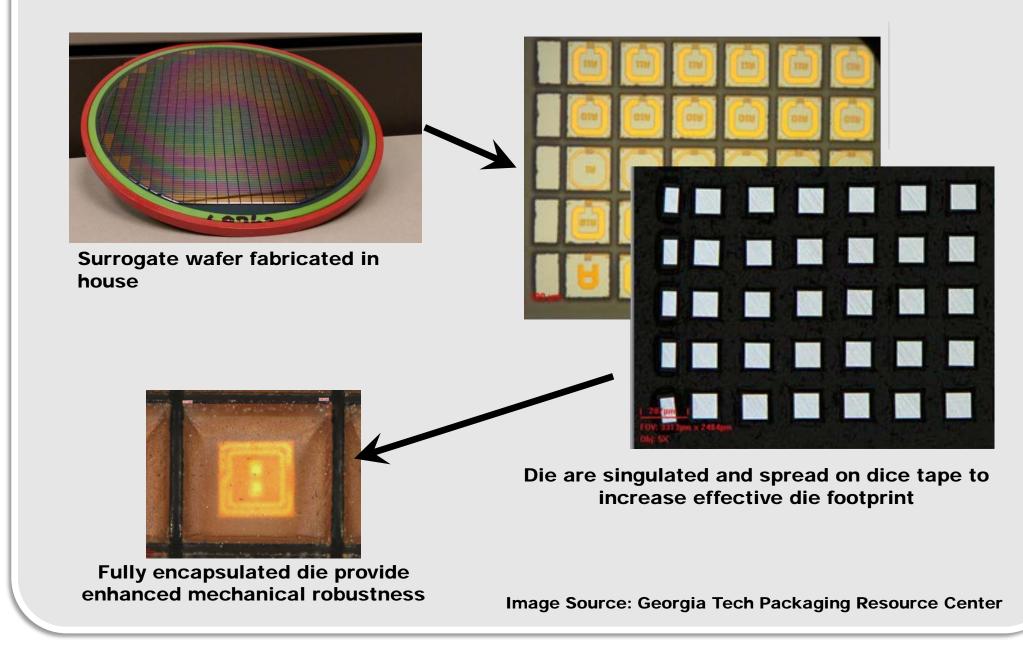
| Dielet Array Local decoding allows single dielet Power On/Communication Simultaneous ATPG scan of entire row (20 dielets) also possible Test Controller Programs and reads back 400 OTP S/Ns with single touchdown Reads raw PUF bits to form a bit mask Integrates with Probe functionality to allow full authentication Provides visibility into each dielet's digital core | |
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This research was developed with funding from the Defense Advanced Research Projects Agency (DARPA). The views, opinions and/or findings expressed are those of the author and should not be interpreted as representing the official views or policies of the Department of Defense or the U.S. Government. Distribution Statement – To Be Completed By DARPA.

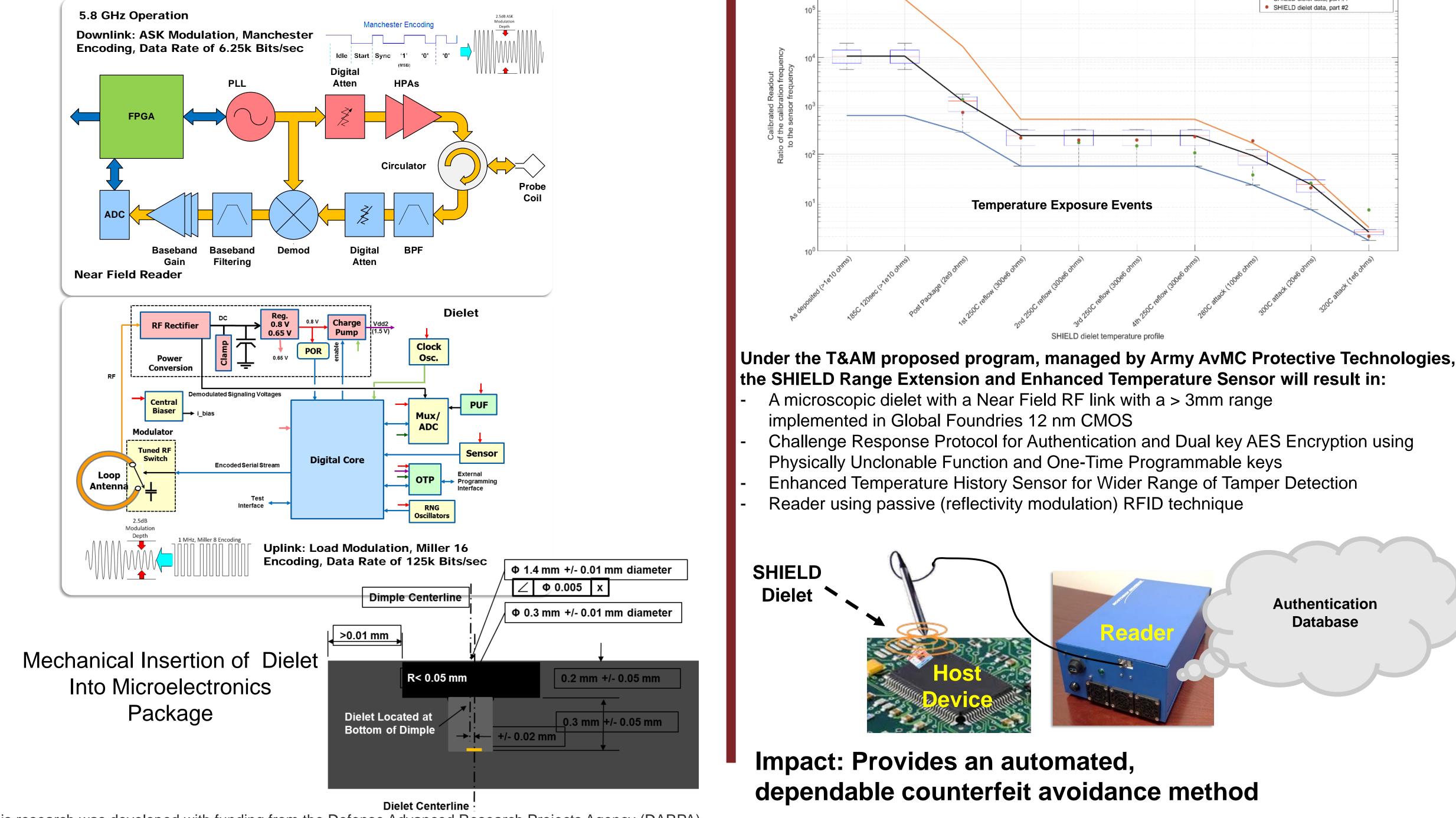
Supply Chain Integrity for Electronics Defense Bryce Winters, Scott Suko, Sam Wanis, Northrop Grumman Team: Sandia National Labs, Georgia Tech Packaging Center, RFID Global Solution

Approach

Dielet Stretching and Encapsulation Protects Dielets and Allows Handling with Standard Tooling

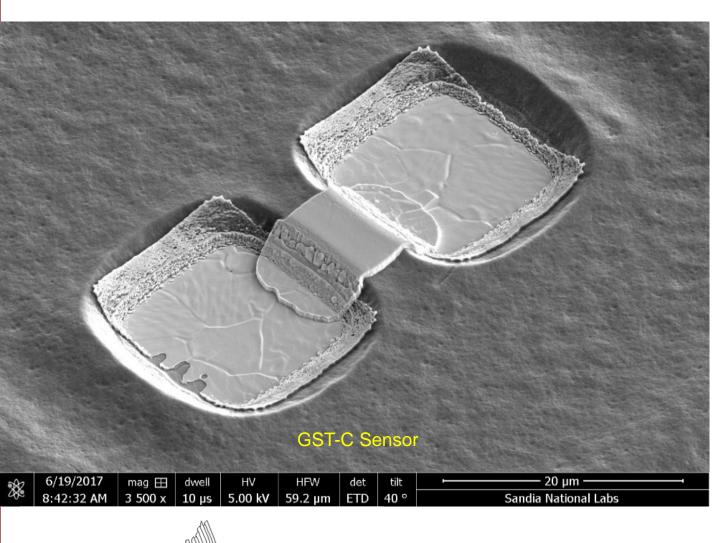


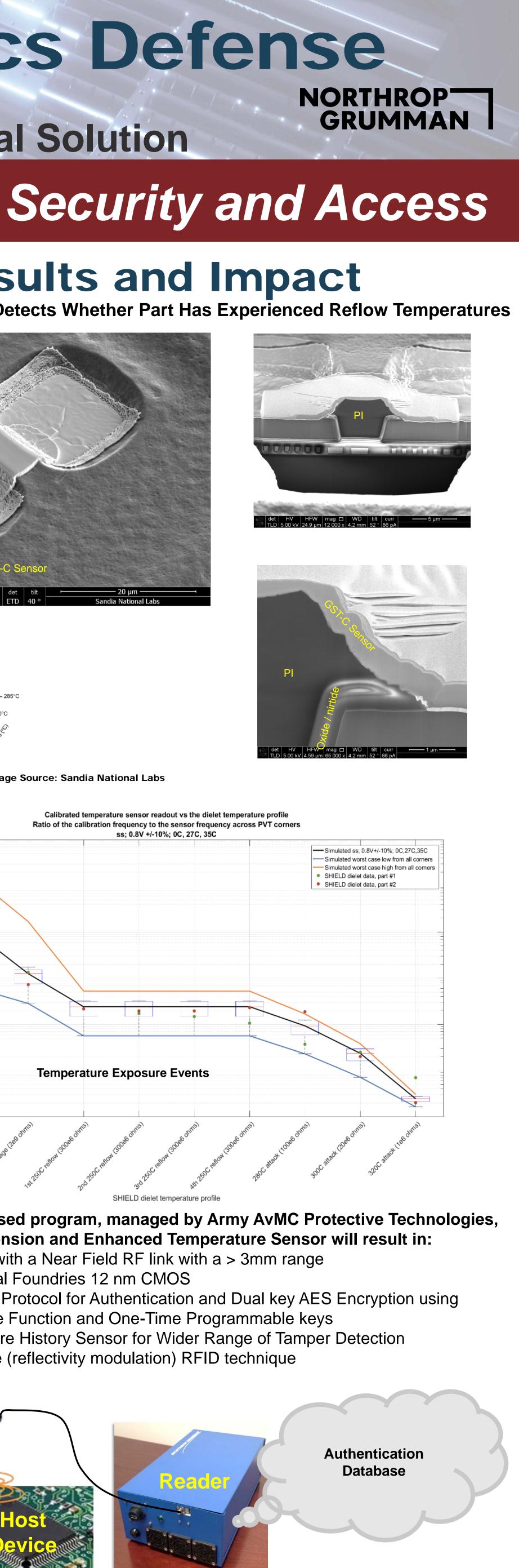
Near Field Reader Architecture Uses Single Coil, Single Frequency System for Simultaneous Power Transfer and Bidirectional Communications

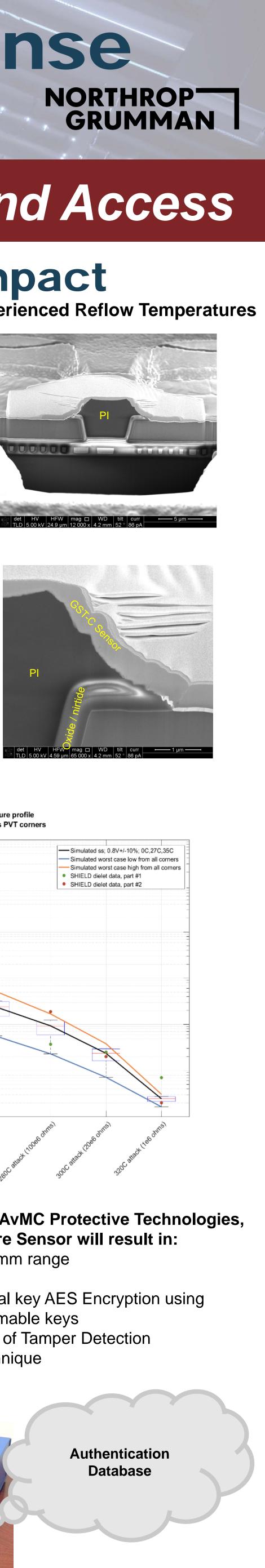


Results and Impact

Temperature Sensor Detects Whether Part Has Experienced Reflow Temperatures







Calibrated temperature sensor readout vs the dielet temperature profile Ratio of the calibration frequency to the sensor frequency across PVT corners ss; 0.8V +/-10%; 0C, 27C, 35C

Image Source: Sandia National Labs

